-	Search Notes		

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/713,047	YUEH, WEN HSIAN	NG
Examiner	Art Unit	
Duo M. Nauron	2695	

SEARCHED			
Class	Subclass	Date	Examiner
455	569.1 556.1 556.2		
	557 558		
	552.1		
	41.1 41.2		
F	575.2		
	566 567		
	90.1 90.2		
	66 344		
	346 349	2/13/2006	DN
Updat	ed	9/20/06	bN
·			
•			

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
		·	

SEAF (INCLUDING S	RCH NOT SEARCH	ES STRATEGY	)
		DATE	EXMR
EAST		2/13/2006	DN